

# Comments and Corrections

---

## Corrections to "Probabilistic Simulation for Reliability Analysis of CMOS VLSI Circuits"<sup>1</sup>

FARID N. NAJM, RICHARD BURCH, PING YONG, AND  
IBRAHIM N. HAJJ

**Abstract**—Due to difficulties with mail service, the authors' corrections to the galley proofs were not incorporated into the above paper.<sup>1</sup>

Manuscript received March 19, 1990.

F. N. Najm, R. Burch, and P. Yong are with the VLSI Design Laboratory, Texas Instruments, Inc., Dallas, TX 75265.

I. N. Hajj is with the Coordinated Science Laboratory, University of Illinois at Urbana-Champaign, Urbana, IL 61801.

IEEE Log Number 9035976.

<sup>1</sup>IEEE *Trans. Computer-Aided Design*, vol. 9, pp. 439-450, Apr. 1990.

The editorial staff apologizes to the authors and readers for this problem.

The corrections are as follows.

1) Equation (3.4) should read:

$$E[I_p] = V_{dd} \times E[G_p(t^+) | G_p(t^-) = 0] \times P(G_p(t^-) = 0) \quad (3.4)$$

2) The left-hand-side of (4.14) should be  $P_{z,lf \rightarrow hf}(t)$ , not  $P_{z,lf \rightarrow hf}(t^+)$ .

3) The table shown under the title and caption of "Table I" ("Table II") is actually Table II (Table I).

4) Equation (A.1) should read:

$$P_{e_p,1}(t^\pm) = P_{e_{1,1}}(t^\pm) + P_{e_{2,1}}(t^\pm) - P_{e_{1,1}}(t^\pm) P_{e_{2,1}}(t^\pm). \quad (A.1)$$